

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY DOCKET NO. 00862.022499.		APPLICATION NO. 10/059,171	
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				APPLICANT TAKAO YONEHARA, et al.			
FILING DATE January 31, 2002				GROUP 2871 2813			

U.S. PATENT DOCUMENTS							
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
TW	6,075,280	06/13/00	Yung et al.	257	620	/	
	6,136,668	10/24/00	Tamaki, et al.	438	462		
	6,186,384	02/13/01	Sawada	225	2		
	6,465,329	10/15/02	Glenn	438	462		
	2002/0076904	06/20/02	Imler	438	462		
TW	2002/0100941	08/01/02	Yonehara, et al.	257	359		

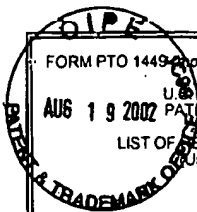
FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT		

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

EXAMINER <i>[Signature]</i>	DATE CONSIDERED 8/30/02
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FORM PTO 1449 (modified) AUG 19 2002 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 00862.022499		APPLICATION NO. 10/059,171	
				APPLICANT TAKAO YONEHARA, et al.			
				FILING DATE January 31, 2002		GROUP 2813 2874	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TW		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
		6,222,513	03/10/1998	Howard, et al.	345	84	
		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
		6,331,208	12/18/2001	Nishida, et al.	117	89	
		6,342,433	01/29/2002	Ohmi, et al.	438	455	
TW		6,382,292	05/07/2002	Ohmi, et al.	156	584	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
TW	EP	1 122 794	08/08/2001	Europe			
	EP	858 110	08/12/1998	Europe			
	EP	849 788	06/24/1998	Europe			
TW	JP	11-316397	11/16/1999	Japan	G02F		Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
TW		Shimoda, T., et al: "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5-8, 1999, New York, NY: IEEE, US, Aug. 1, 1999 (1999-08-01), pages 289-292, XP000933199 ISBN: 0-7803-5411-7.					
EXAMINER				DATE CONSIDERED 8/30/04			

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				APPLICANT Takao Yonehara, et al.		FILING DATE 1-31-02 Currently herewith	
				GROUP 2813 N + Yet Assigned			

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
TW	5,206,749	4/27/93	Zavracky et al.	359	59		
	5,256,562	10/26/93	Vu et al.	437	86		
	5,811,348	9/22/98	Matsushita, et al.	438	455		
	6,107,213	8/22/00	Tayanaka, et al.	438	762		
	5,985,742	11/16/99	Henley, et al.	438	515		
TW	5,856,229	1/5/99	Sakaguchi, et al.	438	406		

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
TW	9-312349	12/2/97	Japan			Abstract	
TW	886 300	12/23/98	EP				

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

EXAMINER <i>Chair</i>	DATE CONSIDERED 8/30/04
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